



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Name and Address:

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|--|------------|------|-----------------------------------|--|---|---|--------------|
| Calibration – Electrical Quantities - DC and LF | | | | | כיוול – גדלים חשמליים - זרם ישר ותדר נמוך | | |
| 1 | A | P | DC Voltage, Sources | ± 1.018 V | 6.5 μV/V | MetCal Automated Calibration Software Manufacturer instructions WI-C104 WI-C100 WI-C103 | Wavetek 9100 |
| 2 | A | P | | ± 10 V | 5.7 μV/V | | Datron 1281 |
| 3 | A | P;T | | 0 mV | 0.12 μV | | Wavetek 4808 |
| 4 | A | P | | (0.1 μV to 200 mV] | 6.81 μV/V | | Wavetek 4912 |
| 5 | A | P | | (200 mV to 2 V] | 3.74 μV/V | | Wavetek 4950 |
| 6 | A | P | | (2V to 20 V] | 3.66 μV/V | | Fluke 5520A |
| 7 | A | P | | (20 V to 200 V] | 5.22 μV/V | | Fluke 734A |
| 8 | A | P | | (200 V to 1050 V] | 5.40 μV/V | | Fluke 5730A |
| 9 | A | T | | (0.1 μV to 200 mV] | 14 μV/V | | Fluke 8508A |
| 10 | A | T | | (200 mV to 1V] | 6.7 μV/V | | |
| 11 | A | T | | (1 V to 10 V] | 5 μV/V | | |
| 12 | A | T | | (10 V to 100 V] | 5 μV/V | | |
| 13 | A | T | | (100 V to 1000 V] | 8.3 μV/V | | |
| 14 | A | P,T | DC Voltage, Measuring Instruments | 0 mV | 0.5 μV | MetCal Automated Calibration Software Manufacturer instructions WI-C100 WI-C103 | Fluke 734A |
| 15 | A | P | | (0.1 μV to 220 mV] | 14.3 μV/V | | Wavetek 4912 |
| 16 | A | P | | (0.22 V to 2.2 V] | 6.8 μV/V | | Wavetek 4808 |
| 17 | A | P | | (2.2 V to 11 V] | 4.5 μV/V | | Datron 1281 |
| 18 | A | P | | (11 V to 22 V] | 4.4 μV/V | | Wavetek 4950 |
| 19 | A | P | | (22 V to 220 V] | 6.4 μV/V | | Fluke 5520A |
| 20 | A | P | | (220 V to 1100 V] | 8.7 μV/V | | Wavetek 9100 |
| | | | | | | | |

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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| 21 | A | T | | (0 mV to 329.9999 mV] | 8.4 μV/V | | Fluke 8508A |
| 22 | A | T | | (329.9999 mV to 3.299999 V] | 15 μV/V | | |
| 23 | A | T | | (3.299999 V to 32.99999 V] | 16 μV/V | | |
| 24 | A | T | | (32.99999 V to 329.999 V] | 26 μV/V | | |
| 25 | A | T | | (329.9999 V to 1000 V] | 26 μV/V | | |
| 26 | A | P;T | DC Current. Sources | 0 μA | 0.6 nA | MetCal | Datron 1281 |
| 27 | A | P;T | | (10 nA to 200 μA] | 14.32 μA/A | Automated Calibration Software | Current clamp Fluke 337 |
| 28 | A | P;T | | (200 μA to 2 mA] | 14.4 μA/A | | Fluke 5730A |
| 29 | A | P;T | | (2 mA to 20 mA] | 1.49 μA/A | | Fluke 8508A |
| 30 | A | P;T | | (20 mA to 200 mA] | 47.78 μA/A | Manufacturer instructions WI-C100 | |
| 31 | A | P;T | | (200 mA to 2 A] | 2.15 μA/A | | |
| 32 | A | P;T | | (2 A to 20 A] | 48.7 μA/A | | |
| 33 | A | P;T | DC Current, Measuring Instruments | 0 μA | 0.007 μA | MetCal | Standard resistors Datron 1281 Wavetek 9100 Wavetek 4808 Wavetek 4950 Fluke 5520A |
| 34 | A | P;T | | (2 nA to 220 μA] | 120 μA/A | Automated Calibration Software | |
| 35 | A | P;T | | (220 μA to 2 mA] | 57 μA/A | Manufacturer instructions | |
| 36 | A | P;T | | (2.2 mA to 22 mA] | 52 μA/A | WI-C100 | |
| 37 | A | P;T | | (22 mA to 220 mA] | 61 μA/A | | |
| 38 | A | P;T | | (220 mA to 2.2 A] | 110 μA/A | | |
| 39 | A | P;T | | (2.2 A to 20 A] | 480 μA/A | | |

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות

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| 57 | A | P;T | | (30 kHz to 100 kHz) | 889.3 μ V/V | | |
| 58 | A | P;T | | (100 kHz to 300kHz) | 889.3 μ V/V | | |
| 59 | A | P;T | | (300 kHz to 1MHz) | 34.6 mV/V | | |
| 60 | A | P;T | | (2 V to 20V) | | | |
| | | | | [1 Hz to 10 Hz] | 1.58 mV/V | | |
| 61 | A | P;T | | (20 Hz to 40 Hz) | 1.57 mV/V | | |
| 62 | A | P;T | | (40 Hz to 100Hz) | 1.17 mV/V | | |
| 63 | A | P;T | | (100Hz to 2 kHz) | 0.93 mV/V | | |
| 64 | A | P;T | | (2 kHz to 10 kHz) | 1.17 mV/V | | |
| 65 | A | P;T | | (10 kHz to 30 kHz) | 2.77 mV/V | | |
| 66 | A | P;T | | (30 kHz to 100 kHz) | 8.1 mV/V | | |
| 67 | A | P;T | | (100 kHz to 300kHz) | 57.8 mV/V | | |
| 68 | A | P;T | | (300 kHz to 1MHz) | 346.47 mV/V | | |
| 69 | A | P;T | | (20V to 200V) | | | |
| | | | | [1 Hz to 10 Hz] | 16 mV/V | MetCal | Datron 1281 |
| 70 | A | P;T | | (20 Hz to 40 Hz) | 13.15 mV/V | | Wavetek 4950 |
| 71 | A | P;T | | (40 Hz to 100Hz) | 12.1 mV/V | Automated Calibration Software | FLUKE 5730A FLUKE 8508A |
| 72 | A | P;T | | (100Hz to 2 kHz) | 10.8 mV/V | Manufacturer instructions | |
| 73 | A | P;T | | (2 kHz to 10 kHz) | 11.9 mV/V | WI-C100 | |
| 74 | A | P;T | | (10 kHz to 30 kHz) | 11.9 mV/V | WI-C106 | |

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| 75 | A | P;T | | (30 kHz to 100 kHz] | 81 mV/V | | |
| 76 | A | P;T | | (100 kHz to 300kHz] | 577.37 mV/V | | |
| 77 | A | P;T | | *(300 kHz to 1MHz] (200 V to 1050 V] | 3465 mV/V | | |
| 78 | A | P;T | | *[1 Hz to 40 Hz] | 141 mV/V | | |
| 79 | A | P;T | | (40 Hz to 10kHz] | 73.4 mV/V | | |
| 80 | A | P;T | | (10kHz to 30 kHz] | 162 mV/V | | |
| 81 | A | P;T | | *(30 kHz to 100 kHz] | 520 mV/V | | |
| 82 | A | P;T | AC Voltage. Measuring Instruments | (0.2 mV to 220 mV] | | MetCal | Datron 1281 |
| 83 | A | P;T | | (10Hz to 20 Hz] | 431 μ V/V | Automated Calibration Software | Wavetek 9100 |
| 84 | A | P;T | | (20 Hz to 40 Hz] | 204 μ V/V | Manufacturer instructions | Wavetek 4808 |
| 85 | A | P;T | | (40 Hz to 20 kHz] | 162 μ V/V | WI-C100 | Wavetek 4950 |
| 86 | A | P;T | | (20 kHz to 50 kHz] | 230 μ V/V | WI-C102 | Fluke 5520A |
| 87 | A | P;T | | (50 kHz to 100 kHz] | 566 μ V/V | WI-C105 | FLUKE 5730A |
| | | | | (100 kHz to 300 kHz] | 1.1 mV/V | | FLUKE 8508A |

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| 88 | A | P;T | | (300 kHz to 500 kHz] | 2.0 mV/V | | |
| 89 | A | P;T | | (500 kHz to 1 MHz] | 3.9 mV/V | | |
| 90 | A | P;T | | (220 mV to 2.2 V] | | | |
| 91 | A | P;T | | (10Hz to 20 Hz] | 325 μ V/V | | |
| 92 | A | P;T | | (20 Hz to 40 Hz] | 134 μ V/V | | |
| 93 | A | P;T | | (40 Hz to 20 kHz] | 62 μ V/V | | |
| 94 | A | P;T | | (20 kHz to 50 kHz] | 93 μ V/V | | |
| 95 | A | P;T | | (50 kHz to 100 kHz] | 136 μ V/V | | |
| 96 | A | P;T | | (100 kHz to 300 kHz] | 489 μ V/V | | |
| 97 | A | P;T | | (300 kHz to 500 kHz] | 1.5 mV/V | | |
| 97 | A | P;T | | (500 kHz to 1 MHz] | 2.7 mV/V | MetCal | |
| 98 | A | P;T | | (2.2 V to 22 V] | | Automated Calibration Software | |
| 99 | A | P;T | | (10Hz to 20 Hz] | 331 μ V/V | Manufacturer instructions | |
| 100 | A | P;T | | (20 Hz to 40 Hz] | 128 μ V/V | WI-C100 | |
| 101 | A | P;T | | (40 Hz to 20 kHz] | 60 μ V/V | WI-C102 | |
| 102 | A | P;T | | (20 kHz to 50 kHz] | 95 μ V/V | WI-C105 | |
| 102 | A | P;T | | (50 kHz to 100 kHz] | 132 μ V/V | | |

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| 103 | A | P;T | | (100 kHz to 300 kHz] | 430 μ V/V | | |
| 104 | A | P;T | | (300 kHz to 500 kHz] | 1.5 mV/V | | |
| 105 | A | P;T | | (500 kHz to 1 MHz] | 2.7 mV/V | | |
| | | | | (22 V to 220 V] | | | |
| 106 | A | P;T | | (10Hz to 20 Hz] | 299 μ V/V | | |
| 107 | A | P;T | | (20 Hz to 40 Hz] | 122 μ V/V | | |
| 108 | A | P;T | | (40 Hz to 20 kHz] | 81 μ V/V | | |
| 109 | A | P;T | | (20 kHz to 50 kHz] | 105 μ V/V | | |
| 110 | A | P;T | | (50 kHz to 100 kHz] | 187 μ V/V | | |
| 111 | A | P;T | | (100 kHz to 300 kHz] | 1.1 mV/V | | |
| 112 | A | P;T | | (300 kHz to 500 kHz] | 5.1 mV/V | | |
| 113 | A | P;T | | (500 kHz to 1 MHz] | 9.3 mV/V | | |
| | | | | (220 V to 1100 V] | | | |
| 114 | A | P;T | | (15 Hz to 50 Hz] | 348 μ V/V | | |
| 115 | A | P;T | | (50 Hz to 1kHz] | 84 μ V/V | Manufacturer instructions WI-C100 | |
| 116 | A | P;T | AC Current Sources | זרם חילופין מחוללי זרם (200 μ A to 2 mA] *[1 Hz to 10 Hz] | 524 μ A/A | MetcalAutomated Calibration Software Manufacturer Instruction WI-C100 | Datron 1281 Wavetek 4950 Fluke 337 |

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| 117 | A | P;T | | [10 Hz to 10 kHz] | 523 μ A/A | | Fluke 5780A Fluke 5725A Fluke 8508A |
| 118 | A | P;T | | (10 kHz to 30 kHz) | 929 μ A/A | | |
| 119 | A | P;T | | *(30 kHz to 100 kHz) | 0.93 mA/A | | |
| 120 | A | P;T | | (2 mA to 20 mA) *[1 Hz to 10 Hz] | 521 μ A/A | | |
| 121 | A | P;T | | [10 Hz to 10 kHz] | 521 μ A/A | | |
| 122 | A | P;T | | (10 kHz to 30 kHz) | 925 μ A/A | | |
| 123 | A | P;T | | *(30 kHz to 100 kHz) | 4.85 mA/A | | |
| 124 | A | P;T | | (20 mA to 200 mA) *[1 Hz to 10 Hz] | 26.64 μ A/A | | |
| 125 | A | P;T | | [10 Hz to 10 kHz] | 522 μ A/A | | |
| 126 | A | P;T | | *(10 kHz to 30 kHz) | 925 μ A/A | | |
| 127 | A | P;T | | (200 mA to 2 A) (10 Hz to 2 kHz) | 925 μ A/A | | |
| 128 | A | P;T | | (2 kHz to 10 kHz) | 1040 μ A/A | | |

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| 129 | A | P;T | | (10 kHz to 30 kHz) (2 A to 20 A) | 3.71 mA/A | | |
| 130 | A | P;T | | (10 Hz to 2 kHz) | 1.2 mA/A | | |
| 131 | A | P;T | | (2kHz to 10kHz) | 3.2mA/A | | |
| 132 | A | P;T | AC Current Measuring Instruments זרם חילופין מכשירי מדידה | (0.1 μA to 220 μA) | | MetCal | Datron 1281 |
| 133 | A | P;T | | [10 Hz to 20Hz] | 487 μA/A | MTS Automated Calibration Software Manufacturer instructions | Wavetek 9100 Wavetek 4808 Wavetek MTS 4950 |
| 134 | A | P;T | | [20 Hz to 40Hz] | 314 μA/A | WI-C100 | Fluke 5520A Fluke 5720A |
| 135 | A | P;T | | [40 Hz to 1 kHz] | 223 μA/A | WI-C102 | Current Coils |
| 136 | A | P;T | | [1 kHz to 5 kHz] | 525 μA/A | | |
| 137 | A | P;T | | (5 kHz to 10 kHz) | 2.2 mA/A | | |
| 138 | A | P;T | | (220 μA to 2.2 mA) | | | |
| 139 | A | P | | [10 Hz to 20Hz] | 347 μA/A | | |
| 140 | A | P;T | | [20 Hz to 40Hz] | 238 μA/A | | |
| 141 | A | P | | [40 Hz to 1 kHz] | 170 μA/A | | |
| | | | | [1 kHz to 5 kHz] | 340 μA/A | | |
| | | | | (5 kHz to 10 kHz) | 2.1 mA/A | | |

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| 142 | A | P;T | | (2.2 mA to 22 mA) [10 Hz to 20Hz] | 363 µA/A | | |
| 143 | A | P;T | | [20 Hz to 40Hz] | 245 µA/A | | |
| 144 | A | P;T | | [40 Hz to 1 kHz] | 178 µA/A | | |
| 145 | A | P;T | | [1 kHz to 5 kHz] | 365 µA/A | | |
| 146 | A | P;T | | (5 kHz to 10 kHz) | 1.95 mA/A | | |
| 147 | A | P;T | | (22 mA to 220 mA) [10 Hz to 20Hz] | 360 µA/A | | |
| 148 | A | P;T | | [20 Hz to 40Hz] | 243 µA/A | | |
| 149 | A | P;T | | [40 Hz to 1 kHz] | 171 µA/A | | |
| 150 | A | P;T | | [1 kHz to 5 kHz] | 321 µA/A | | |
| 151 | A | P;T | | (5 kHz to 10 kHz) | 1.6 mA/A | | |
| 152 | A | P;T | | (220 mA to 2.2 A) [20 Hz to 1 kHz] | 344 µA/A | | |
| 153 | A | P;T | | (1 kHz to 5 kHz) | 674 µA/A | | |
| 154 | A | | | (5 kHz to 10 kHz) | 8.4 mA/A | | |
| 155 | A | P;T | | (2.2 A to 11 A) (40 Hz to 1 kHz) | 558 µA/A | | |

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| 156 | A | P;T | | (1 kHz to 5 kHz] | 1.2 mA/A | | |
| 157 | A | P;T | | (5 kHz to 10 kHz] | 4.3 mA/A | | |
| 158 | A | P;T | | (11 A to 20.5 A] | 7.23 mA/A | | |
| | | | | (45 Hz to 100 Hz] | | | |
| 159 | A | P;T | | (100Hz to 1 kHz] | 7.6 mA/A | | |
| 160 | A | P;T | | (1 kHz to 5 kHz] | 41 mA/A | | |
| 161 | A | P;T | | (20 A to 32 A] | 8.2 mA/A | | |
| | | | | (10 Hz to 440 Hz] | 39 mA/A | | |
| 162 | A | P;T | | (32 A to 160 A] | | | |
| | | | | [10 Hz to 100 Hz] | 68 mA/A | | |
| 163 | A | P;T | (160 A to 200 A] | | | | |
| | | | (10 Hz to 440 Hz] | 195 mA/A | | | |
| 164 | A | P;T | (200 A to 1000 A] | | | | |
| | | | [10 Hz to 50 Hz] | | | | |
| 165 | A | P;T | DC Resistance, Resistors Shunts | התנגדות זרם ישר, נגדים מיצד זרם | 0.0001 Ω | 160 mΩ/Ω | Manufacturer instructions WI-C100 WI-C101 WI-C103 DMM 1281A DMM 34401A FLUKE 8508A DMM 6.5digit |
| 166 | A | P;T | | 0.0002 Ω | 79 mΩ/Ω | | |
| 167 | A | P;T | | 0.0005 Ω | 31 mΩ/Ω | | |
| 168 | A | P;T | | 0.005 Ω | 310 μΩ/Ω | | |
| 169 | A | P;T | | 0.001 Ω | 1.54 mΩ/Ω | | |
| 170 | A | P;T | | 0.01 Ω | 1.5 mΩ/Ω | | |
| 171 | A | P;T | | 0.1 Ω | 2.3 mΩ/Ω | | |
| 172 | A | P;T | | 0 Ω | 5 μΩ | | |

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The certificate attached is an integral part of the schedule and is numbered identically זהו למספר הנספח המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|--|------------|------|-----------------------------|--|---|--|---------|
| Calibration – Electrical Quantities - DC and LF | | | | | כיוול – גדלים חשמליים - זרם ישר ותדר נמוך | | |
| 173 | A | P;T | | 1 Ω | 1.6 m Ω / Ω | | |
| 174 | A | P;T | | 1.9 Ω | 1.41 m Ω / Ω | | |
| 175 | A | P;T | | 10 Ω | 1 m Ω / Ω | | |
| 176 | A | P;T | | 19 Ω | 0.9 m Ω / Ω | | |
| 177 | A | P;T | | 50 Ω | 952 $\mu\Omega$ / Ω | | |
| 178 | A | P;T | | 100 Ω | 910 $\mu\Omega$ / Ω | | |
| 179 | A | P;T | | 190 Ω | 870 $\mu\Omega$ / Ω | | |
| 180 | A | P;T | | 1 k Ω | 9.01 $\mu\Omega$ / Ω | | |
| 181 | A | P;T | | 1.9 k Ω | 17 $\mu\Omega$ / Ω | | |
| 182 | A | P;T | | 10 k Ω | 89.4 $\mu\Omega$ / Ω | | |
| 183 | A | P;T | | 50 k Ω | 168.9 $\mu\Omega$ / Ω | | |
| 184 | A | P;T | | 100 k Ω | 0.92 m Ω / Ω | Manufacturer instructions WI-C100 WI-C101 WI-C103 | |
| 185 | A | P;T | | 190 k Ω | 1.69 m Ω / Ω | | |
| 186 | A | P;T | | 1 M Ω | 10.9 $\mu\Omega$ / Ω | | |
| 187 | | P;T | | 1.9 M Ω | 19 $\mu\Omega$ / Ω | | |

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|--|------------|------|-----------------------------|--|--|--------------------------------------|---------|
| Calibration – Electrical Quantities - DC and LF | | | | | כיוול – גדלים חשמליים - זרם ישר ותדר נמוך | | |
| 188 | A | P;T | | 10 MΩ | 251 μΩ/Ω | | |
| 189 | A | P;T | | 19 MΩ | 351 μΩ/Ω | | |
| 190 | A | P;T | | 100 MΩ | 4.65 mΩ/Ω | | |
| 191 | A | P;T | | 1 GΩ | 317 μΩ/Ω | | |
| 192 | A | P;T | | [High Amp. Std. Shunt] 0.0005Ω±0.5 Ω @ 141A | 0.016% | Manufacturer instructions WI-C101 | |
| 193 | A | P;T | | 0.0005Ω±0.5 Ω @ 224A | 0.016% | | |
| 194 | | P;T | | 0.0005Ω±0.5 Ω @ 300A | 0.016% | | |
| 195 | A | P;T | | 0.0001Ω±0.5 Ω @ 10A±300A | 0.11% | | |

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|--|------------|------|--------------------------------------|--|--|---------------------|--|-------------------|-----------|--------------------------------|-------------------------------|
| Calibration – Electrical Quantities - DC and LF | | | | | כיוול – גדלים חשמליים - זרם ישר ותדר נמוך | | | | | | |
| 196 A | P;T | P;T | DC Resistance, Sources | התנגדות זרם ישר, מחוללים (0 Ω to 2 G Ω) | 17 μΩ/Ω + 4μΩ | MetCal | Wavetek 9100 Fluke 5522A Datron 1281 | | | | |
| 197 A | P;T | | | | | | | (0 Ω to 20 Ω) | 9 μΩ/Ω | | Wavetek 4808 |
| 198 A | P;T | | | | | | | (20 Ω to 200 Ω) | 8.98 μΩ/Ω | Automated Calibration Software | Standard resistance |
| 199 A | P;T | | | | | | | (200 Ω to 2 kΩ) | 9.29 μΩ/Ω | Manufacturer instructions | Wavetek 4950 |
| 200 A | P;T | | | | | | | (2 kΩ to 20 kΩ) | 9.22 μΩ/Ω | WI-C100 | FLUKE 5730A |
| 201 A | P;T | | | | | | | (20 kΩ to 200 kΩ) | 9.41 μΩ/Ω | WI-C101 | FLUKE 8508A |
| 202 A | P;T | | | | | | | (200 kΩ to 2 MΩ) | 11.5 μΩ/Ω | WI-C103 | *Traceable but not Accredited |
| 203 A | P;T | | | | | | | (2 MΩ to 20 MΩ) | 313 μΩ/Ω | | |
| 204 A | P;T | | | | | | | (20 MΩ to 200 MΩ) | 6.9 mΩ/Ω | | |
| 205 A | P;T | | | | | | | (200 MΩ to 2 GΩ) | 0.18% | | |
| 206 A | P;T | | | | | | | (2 GΩ to 100 GΩ) | 0.18% | | |
| 207 A | P;T | P;T | DC Resistance, Measuring Instruments | התנגדות זרם ישר, מכשירי מדידה (1 μΩ to 10 Ω) | 21 μΩ/Ω | MetCal | Wavetek 4950 | | | | |
| 208 A | P;T | | | | | | | (10 Ω to 100 Ω) | 9 μΩ/Ω | | Datron 1281 |
| 209 A | P;T | | | | | | | (100 Ω to 10 kΩ) | 20 μΩ/Ω | Automated Calibration Software | Wavetek 9100 |
| 210 A | P;T | | | | | | | (10 kΩ to 100 kΩ) | 8 μΩ/Ω | Manufacturer instructions | QCC 23-135 |
| 211 A | P;T | | | | | | | (100 kΩ to 1 MΩ) | 6 μΩ/Ω | WI-C100 | |
| 212 A | P;T | | | | | | | (1 MΩ to 10 MΩ) | 30 μΩ/Ω | WI-C101 | |
| 213 A | P;T | | | | | | | (10 MΩ to 100 MΩ) | 199 μΩ/Ω | | |
| 214 A | P;T | | | | | | | (100 MΩ to 1 GΩ) | 517 μΩ/Ω | | |
| 215 A | P;T | | | (10 GΩ to 100 GΩ) | 8.4 mΩ/Ω | | | | | | |

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|--|------------|------|---|--|---|--|---|
| Calibration – Electrical Quantities - DC and LF | | | | | | כיוול – גדלים חשמליים - זרם ישר ותדר נמוך | |
| 216 | A | P;T | Std Resistors, MFC source Measuring Instruments | גדים סטנדרטיים 1 Ω | 7 μΩ/Ω | Manufacturer instructions WI-C100 WI-C101 | |
| 217 | A | P;T | | כילים רב-תחומיים 1.9 Ω | 111 μΩ/Ω | | |
| 218 | A | P;T | | מכשירי מדידה 10 Ω | 8 μΩ/Ω | | |
| 219 | A | P;T | | 19 Ω | 27 μΩ/Ω | | |
| 220 | A | P;T | | 100 Ω | 8 μΩ/Ω | | |
| 221 | A | P;T | | 190 Ω | 12 μΩ/Ω | | |
| 222 | A | P;T | | 1 kΩ | 8 μΩ/Ω | | |
| 223 | A | P;T | | 1.9 kΩ | 8 μΩ/Ω | | |
| 224 | A | P;T | | 10 kΩ | 3.5 μΩ/Ω | | |
| 225 | A | P;T | | 19 kΩ | 8 μΩ/Ω | | |
| 226 | A | P;T | | 100 kΩ | 13 μΩ/Ω | | |
| 227 | A | P;T | | 190 kΩ | 11 μΩ/Ω | | |
| 228 | A | P;T | | 1 MΩ | 16 μΩ/Ω | | |
| 229 | A | P;T | | 1.9 MΩ | 23 μΩ/Ω | | |
| 230 | A | P;T | | 10 MΩ | 47 μΩ/Ω | | |
| 231 | A | P;T | 19 MΩ | 57 μΩ/Ω | | | |
| | | | קיבול Measuring Instruments | (0.5 nF to 4 nF] Up to 350 Hz] | 247 μF/F | MetCal Automated | Wavetek 9100 Standard Capacitors Fluke 5520 A |

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|--|------------|------|-----------------------------|--|---|--|--|
| Calibration – Electrical Quantities - DC and LF | | | | | | כיוול – גדלים חשמליים - זרם ישיר ותדר נמוך | |
| 232 | A | P;T | | | | Calibration Software Manufacturer instructions WI-C100 | GR Capacitance Decade Standard Capacitors FLUKE 5502E FLUKE 5522A |
| 233 | A | P;T | | (350 Hz to 1.5 kHz) (4 nF to 40 nF) | 2.5 mF/F | | |
| 234 | A | P;T | | Up to 350 Hz] | 4.2 mF/F | | |
| 235 | A | P;T | | (350 Hz to 1.5 kHz) (40 nF to 400 nF) | 4.2 mF/F | | |
| 236 | A | P;T | | Up to 350 Hz] | 15.6 mF/F | | |
| 237 | A | P;T | | (350 Hz to 1.5 kHz) (400 nF to 4 μF] | 15.66 mF/F | | |
| 238 | A | P;T | | Up to 350 Hz] | 1.2 mF/F | | |
| 239 | A | P;T | | (350 Hz to 1.5 kHz) (4 μF to 40 μF] | 1.2 mF/F | | |
| 240 | A | P;T | | Up to 350 Hz] | 769 μF/F | | |
| 241 | A | P;T | | (350 Hz to 1.5 kHz) (40 μF to 400 μF] | 769 μF/F | | |
| 242 | A | P;T | | Up to 350 Hz] | 501 μF/F | | |
| 243 | A | P;T | | (350 Hz to 1.5 kHz) (400 μF to 4 mF] | 501 μF/F | | |
| 244 | A | P;T | | Up to 350 Hz] | 1.2 mF/F | | |
| 245 | A | P;T | | (350 Hz to 1.5 kHz) | 1.2 mF/F | | |
| | | | | (4 mF to 40 mF] | | | |

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|--|------------|------|--|--|--|---|--------------------------------------|
| Calibration – Electrical Quantities - DC and LF | | | | | | כיוול – גדלים חשמליים - זרם ישיר ותדר נמוך | |
| 246 | A | P;T | | Up to 350 Hz] | 1.2 mF/F | WI-C100 | |
| 247 | A | P;T | | (350 Hz to 1.5 kHz] | 1.2 mF/F | | |
| 248 | A | P;T | Capacitance, Capacitors | קיבול, קבלים 0.001 μF | 1000 Hz | 6 mF/F | Manufacturer instructions WI-C100 |
| 249 | A | P,T | | 0.005 μF | 1000 Hz | 262 μF/F | |
| 250 | A | P,T | | 0.01 μF | 1000 Hz | 595 μF/F | |
| 251 | A | P,T | | 0.05 μF | 1000 Hz | 137 μF/F | |
| 252 | A | P,T | | 0.1 μF | 1000 Hz | 92 μF/F | |
| 253 | A | P | | Phase angle, Measurement Phase angle meters | זווית מופע מכשירי מדידה מדי זווית מופע (0° to 90°) Frequency: [45 Hz to 65 Hz] | 0.58° | |
| 254 | | P | Frequency: [65 Hz to 500 Hz] Parameters: V: 32 mV to 600 V I: 32 mA to 20 A Alternating V: 10 mV to 5 V When current transducer not allowed | | 0.21° | Manufacturer instructions WI-C108 | |

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

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|--|------------|------|---|---|--|--|---|
| Calibration – Electrical Quantities - DC and LF | | | | | כיוול – גדלים חשמליים - זרם ישר ותדר נמוך | | |
| 255 | A | P,T | AC Power, Measurement Power Meters הספק מתח חילופין מדי הספק | [1mW to 20 kW] Power factor: [0– 1] Frequency: [45 Hz to 65Hz] | 3.5 % | MetCal Automated Calibration Software | Fluke 5520A Fluke 5522A |
| 256 | A | P,T | Power factor, Measurement Power Meters מקדם הספק מדידה מדי הספק | [0– 1] Power: [1mW to 20 kW] Frequency: [45 Hz to 65Hz] | 0.14 | Manufacturer instruction WI-C108 | Electrical Test Equipment calibrator |
| 257 | A | P,T | DC Power, Measurement Power Meters הספק מתח ישר מדי הספק | [10 mW to 20 kW] | 0.5 % | | |
| 258 | A | P,T | Continuity resistance Resistance, measuring instruments התנגדות רציפות, מכשירי מדידת התנגדות | 0.20 Ω to 20 Ω | 1.5% | MetCal Automated Calibration Software | TRANSMILLE 3200 Electrical Test Equipment Calibrator |
| 259 | A | P,T | | 20 Ω to 200 Ω | 1.2% | Manufacturer instructions | |
| 260 | A | P,T | | 200 Ω to 2 kΩ | 1.2% | | |
| 261 | A | P,T | Continuity current Current measuring instruments זרם רציפות מכשירי מדידת זרם | (0 mA to 320 mA) | 4% | WI-C107 | |
| 262 | A | P,T | Insulation resistance Resistance, measuring instruments התנגדות של בידוד מכשירי מדידת התנגדות | 0.01MΩ to 5.00 MΩ | 3.2% | MetCal Automated Calibration Software | TRANSMILLE 3200 Electrical Test Equipment Calibrator |
| 263 | A | P,T | | 5 MΩ to 2 GΩ | 3.6% | Manufacturer instructions WI-C107 | |
| 264 | A | P,T | | 2 G Ω to 10 GΩ | 5.8% | | |
| 265 | A | P,T | | 10 GΩ to 1 TΩ | 5.8% | | |

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

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|--|------------|------|--|---|---|---|--|-----------|
| Calibration – Electrical Quantities - DC and LF | | | | | כיוול – גדלים חשמליים - זרם ישר ותדר נמוך | | | |
| 266 | A | P,T | Residual current AC Residual Current, Sensing Devices (RCD) | זרם חילופין שיורי (מכשירי חישה (RCD)) (Up to 5 Sec.] 3.00 mA to 10.00 mA | 2 mA/A | MetCal Automated Calibration Software Manufacturer instructions WI-C107 | TRANSMILLE 3200 Electrical Test Equipment Calibrator | |
| 267 | A | P,T | | | 10.1 mA to 100 mA | | | 1.39 mA/A |
| 268 | A | P,T | | | 101 mA to 1 A | | | 7.81 mA/A |
| 269 | A | P,T | | | 1.01 A to 3 A | | | 34.8 mA/A |
| 270 | A | P,T | | | (< 190 m Sec.] 3 mA to 10mA | | | 6 mA/A |
| 271 | A | P,T | | | 10.1 mA to 100 mA | | | 6.5 mA/A |
| 272 | A | P,T | | | 101 mA to 1 A | | | 5 mA/A |
| 273 | A | P,T | | | 1.01 A to 3A | | | 5.6 mA/A |
| 274 | A | P,T | Residual current duration AC Loop Resistance Loop Testing Devices. | התנגדות לולאה בזרם חילופין מכשירי בדיקת לולאה | 0.05 Ω | Manufacturer instructions WI-C107 | | |
| 275 | A | P,T | | | 0.1 Ω | | | 0.0079 Ω |
| 276 | A | P,T | | | 0.22 Ω | | | 0.0087 Ω |
| 277 | A | P,T | | | 0.33 Ω | | | 0.0097 Ω |
| 278 | A | P,T | | | 0.5 Ω | | | 0.011 Ω |
| 279 | A | P,T | | | | | | |

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|--|------------|------|---|--|---|--|--|---|
| Calibration – Electrical Quantities - DC and LF | | | | | | כיוול – גדלים חשמליים - זרם ישר ותדר נמוך | | |
| 280 | A | P,T | | 1 Ω | 0.017 Ω | | | |
| 281 | A | P,T | | 5 Ω | 0.067 Ω | | | |
| 282 | A | P,T | | 10 Ω | 0.13 Ω | | | |
| 283 | A | P,T | | 100 Ω | 1.3 Ω | | | |
| | | | | 1 k Ω | 13 Ω | | | |
| 284 | A | P,T | Auto Loop Resistance AC Auto Loop Resistance. Loop Testing devices. | התנגדות לולאה בזרם AC מכשירי בדיקת לולאה. | 1 Ω | 0.06Ω | MetCal Automated Calibration Software Manufacturer instructions | TRANSMILLE 3200 Electrical Test Equipment Calibrator |
| 285 | A | P,T | Earth Bond Resistance | התנגדות בדיקת חיבור להארקה מכשירי PAT | 0.05 Ω | 0.0049 Ω | WI-C107 | |
| 286 | A | P,T | Bond Resistance | | 0.1 Ω | 0.0053 Ω | | |
| 287 | A | P,T | PAT (Portable Appliance Tester) | | 0.22 Ω | 0.0059 Ω | | |
| 288 | A | P,T | | | 0.33 Ω | 0.0065 Ω | | |
| 289 | A | P,T | | | 0.5 Ω | 0.0076 Ω | | |
| 290 | A | P,T | | | 1 Ω | 0.010 Ω | | |
| 291 | A | P,T | | | 5 Ω | 0.033 Ω | | |
| 292 | A | P,T | | | 10 Ω | 0.062 Ω | | |
| 293 | A | P,T | | | 100 Ω | 0.582 Ω | | |
| 294 | A | P,T | | | 1 k Ω | 5.77 Ω | | |
| 295 | A | P,T | Earth Bond Current Bond current, | זרם בדיקת חיבור להארקה | 100.0 mA | 9.3 mA | | |
| 296 | A | P,T | PAT (Portable Appliance Tester) | מכשירי PAT | 10.00 A | 0.24 A | | |
| 297 | A | P,T | | | 30.00 A | 0.59 A | | |
| 298 | A | P,T | Insulation Resistance | התנגדות בידוד, | 0 MΩ | 0.0074 MΩ | | |

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| Calibration – Electrical Quantities - DC and LF | | | | | | כיוול – גדלים חשמליים - זרם ישר ותדר נמוך | | |
| 299 | A | P,T | Resistance, PAT (Portable Appliance Tester) | 0.01 MΩ to 5 MΩ | 3 % | | | |
| 300 | A | P,T | | 5MΩ to 2 GΩ | 3.5 % | | | |
| 301 | A | P,T | Leakage Current, PAT (Portable Appliance Tester) | זליגת זרם להארקה מכשירי PAT | 2.000 mA | MetCal Automated Calibration Software Manufacturer instructions | TRANSMILLE 3200 Electrical Test Equipment Calibrator | |
| 302 | A | P,T | | 4.700 mA | 0.084 mA | | | |
| 303 | A | P,T | | 7.700 mA | 0.136 mA | | | |
| 304 | A | P,T | Flash Voltage PAT (Portable Appliance Tester) | מתח פריצת בידוד מכשירי PAT | Class 1 (1.5 kV) (1 kV to 1.8 kV] | WI-C107 WI-C100 | | |
| 305 | A | P,T | | | 1000 V | | | 57 V |
| 306 | A | P,T | | | 1500 V | | | 81 V |
| | | | | Class 2 (3 kV) (2 kV to 3 kV] | | | | |
| | | | | 3000 V | 151 V | | | |
| 307 | A | P,T | Flash Current PAT (Portable Appliance Tester) | זרם פריצת בידוד מכשירי PAT | (1 mA to 3 mA] 1.00 mA | | | |
| 308 | A | P,T | Line Voltage Measurement of line voltage | מתח רשת חשמל, מדידת מתח רשת חשמל | (200 V (rms)) to 260 V(rms)] | | | |
| 309 | A | P,T | Breakdown/Hipot Measurement of high voltage | מדידת מתח גבוה | (3 kV AC @ 50 Hz) | Manufacturer instructions WI-C107 | | |
| | | | | | 1.00 kV | | | 0.05 kV |
| 310 | A | P,T | | | 2.00 kV | | | 0.06 kV |
| 311 | A | P,T | | | 3.00 kV | | | 0.06 kV |
| 312 | A | P,T | | | (12 kV AC @ 50 Hz) | | | |

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|--|------------|------|-----------------------------|--|---|--|---|
| Calibration – Electrical Quantities - DC and LF | | | | | | כיוול – גדלים חשמליים - זרם ישר ותדר נמוך | |
| 313 | A | P,T | | 4.00 kV | 0.07 kV | | |
| 314 | A | P,T | | 6.00 kV | 0.08 kV | | |
| 315 | A | P,T | | 8.00 kV | 0.10 kV | | |
| 316 | A | P,T | | 10.00 kV | 0.11 kV | | |
| 317 | A | P,T | | (25 kV AC @ 50 Hz) 12 kV to 25 kV | 1.2% O.R. | | |
| 318 | A | P,T | | 3 kV DC 1.00 kV | 0.05 kV | | |
| 319 | A | P,T | | 2.00 kV | 0.06 kV | | |
| 320 | A | P,T | | 3.00 kV | 0.06 kV | | |
| 321 | A | P,T | | (12 kV DC) 4.00 kV | 0.07 kV | Manufacturer instructions WI-C107 | HV Probe 80K-40 DMM TRANSMILLE 3200 |
| 322 | A | P,T | | 6.00 kV | 0.08 kV | | |
| 323 | A | P,T | | 8.00 kV | 0.09 kV | | |
| 324 | A | P,T | | 10.00 kV | 0.10 kV | | |
| 325 | A | P,T | | 12.00 kV | 0.12 kV | | |
| 326 | A | P,T | | (40 kV DC) 12 kV to 40 kV | 1.0% O.R. | | |

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|--|------------|------|--|--|--|---------------------|--|
| <i>Calibration – Electrical Quantities - DC and LF</i> | | | | | <i>כיוול – גדלים חשמליים - זרם ישר ותדר נמוך</i> | | |
| | | | Measurement of current at high voltage | מדידת זרם במתח גבוה | 1 kV AC @ 50 Hz | | |
| 327 | A | P,T | | | 200 µA | 1.7 µA | |
| 328 | A | P,T | | | 2.00 mA | 0.04 mA | |
| 329 | A | P,T | | | 20.00 mA | 0.16 mA | |
| 330 | A | P,T | | | 1 kV DC | | |
| 331 | A | P,T | | | 200 µA | 1.7 µA | |
| 332 | A | P,T | | | 2.00 mA | 0.04 mA | |
| 333 | A | P,T | | | 20.00 mA | 0.16 mA | |
| | | | DC High Voltage, Source | מחוללי מתח גבוה ישר | 40 kV DC) | | |
| 334 | A | P,T | | | 1 kV to 40 kV | 2.4% O.R. | SPELLMAN SL40P2000 HV Probe 80K-40 DMM |

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The certificate attached is an integral part of the schedule and is numbered identically זהו למספר הנספח והוא נפרד ממנו ומספרה זהה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח והוא נפרד ממנו ומספרה זהה חלק בלתי נפרד ממנו ומספרה זהה

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|---|------------|------|---|--|---|--|--|
| Calibration – Electrical Quantities - RF Frequency, Time | | | | | | כיוול – גדלים חשמליים - תדר גבוה, זמן | |
| 335 | A | P | תדר, מחוללי תדר Frequency, Sources | [0.037 Hz to 10 MHz] | 10^{-11} (24 h) | MetCal WI-C102 WI-C105 WI-C106 | FLUKE 910R Wavetek 9500 H.P.5248 M H.P. 53132 A Via GPS System With Ref. Locked to 910R |
| 336 | A | P | | [10 MHz to 3.2 GHz] | 5×10^{-9} (0.3 h) | MetCal WI-C102 WI-C105 WI-C106 | FLUKE 910R Wavetek 9500 H.P.5248 M H.P. 53132 A Via GPS System With Ref. Locked to 910R (with 9500 + 9530) |
| 337 | A | T | | [10 MHz to 3.2 GHz] | 4.8×10^{-5} (0.3 h) | MetCal WI-C102 WI-C105 WI-C106 | Wavetek 9500 H.P.5248 M H.P. 53132 A With Internal Reference |
| 338 | A | P | תדר, מוני תדר Frequency, Counters | [0.1 Hz to 100 MHz] | 4.8×10^{-9} (0.3 h) | WI-C102 | With Ref. Locked to 910R |
| 339 | A | P | | [100 MHz to 3 GHz] | 4.8×10^{-10} (0.3 h) | WI-C105 WI-C106 | With Ref. Locked to 910R (with 9500 + 9530) |
| 340 | A | T | | [0.1 Hz to 3 GHz] | 1.4×10^{-5} (0.3 h) | | With Internal Reference |
| 341 | A | P;T | Timers, stopwatches | שעוני עצר, מוני זמן [1 sec to 24 hr] | 0.1 sec | Manufacturer instructions WI-C070 | השוואה למדיד אב |

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The certificate attached is an integral part of the schedule and is numbered identically זהו למספר הנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|---|------------|------|---|---|---|--|--|
| Calibration – Electrical Quantities - RF Frequency, Time | | | | | | כיוול – גדלים חשמליים - תדר גבוה, זמן | |
| 342 | A | P;T | Oscilloscope Time markers function: Square wave, Pulse, Narrow Triangle | ציר אופקי במשקף תנודות [0.45 ns to 55 sec] | 0.038 μ s/s | Software MetCal Software WI-C102 | Wavetek 9500 Fluke 910R External reference input in the range 1 MHz to 20 MHz |
| 343 | A | P;T | Oscilloscope Amplitude Square Wave | ציר אנכי במשקף תנודות Input impedance 1 M Ω | 10 mV/V + 10 μ V | MetCal Software WI-C102 WI-C105 WI-C106 | Wavetek 9500 Fluke 910R External reference input in the range 1 MHz to 20 MHz |
| 344 | A | P;T | | Peak to peak amplitude (40 μ V to 1 mV] (1 mV to 200 V] | | | |
| 345 | A | P;T | Oscilloscope Amplitude Square Wave | ציר אנכי במשקף תנודות Input impedance 50 Ω | 10 mV/V + 10 μ V | MetCal Software WI-C102 WI-C105 WI-C106 | Wavetek 9500 |
| 346 | A | P;T | | Peak to peak amplitude (40 μ V to 1 mV pk-pk] (1 mV to 5 V pk-pk] | | | |
| 347 | A | P;T | Oscilloscope Rise Time | זמן עליית האות של משקף תנודות Rise time, From 150 ps] | 14 ps | MetCal Software WI-C102 WI-C105 WI-C106 | Wavetek 9500 |
| 348 | A | P;T | Oscilloscope Bandwidth: | רחב סרט של משקף תנודות [0.1 Hz to 300 MHz] | 0.23 db | MetCal Software WI-C102 WI-C105 WI-C106 | Wavetek 9500 |
| 349 | A | P;T | | [300 MHz to 550 MHz] | 0.23 db | | |
| 350 | A | P;T | | [550 MHz to 1.1GHz] | 0.29 db | | |

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Schedule of Accreditation

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|---|------------|------|--------------------------------|----------------------------|--|--|---------------------|----------------------|
| Calibration – Electrical Quantities - RF Frequency, Time | | | | | | כיוול – גדלים חשמליים - תדר גבוה, זמן | | |
| 351 | A | P;T | | | [1.1 GHz to 3.2 GHz] | 0.36 db | | |
| 352 | A | P;T | Oscilloscope | מישוריות האות כתלות בתדר | [0.1 Hz to 300 MHz] | 2.3 % | MetCal Software | Wavetek 9500 |
| 353 | A | P;T | Flatness | ביחס לתדר הייחוס | [300 MHz to 550 MHz] | 3.8 % | WI-C102 | Leveled Sine Wave |
| 354 | A | P;T | | | [550 MHz to 1.1 GHz] | 4.9 % | WI-C105 | Amplitude |
| 355 | A | P;T | | | [1.1 GHz to 3.2 GHz] | 6.0 % | WI-C106 | 50 kHz Ref |
| 356 | A | P;T | Oscilloscope Input Capacitance | קיבול כניסה של משקף תנודות | [1 pF to 65 pF] | 7 mF/F | MetCal Software | Wavetek 9500 |
| | | | | | | | WI-C102 | Input impedance 50 Ω |
| | | | | | | | WI-C100 | |

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|--|------------|------|--|--|--|--|--|
| Calibration – Mechanical Quantities - Form, Angle | | | | | | כיוול – גדלים מכניים - צורה, זווית | |
| 357 | A | P | Flank Angle Screw Plug Gauges (parallel) including check and setting Plug | זווית השן מדיד הברגה זכר מקביל Plug Diameter [1 mm to 305 mm] | [2+(800/M×P)] Minutes of arc | WI-C020 | M is projector magnification and P is pitch in mm |
| 358 | A | P | Flank angle Screw Plug Gauges (taper) | זווית השן מדיד הברגה זכר קוני Plug Diameter [1 mm to 305 mm] | [2+(800/M×P)] Minutes of arc | WI-C020 | M is projector magnification and P is pitch in mm |
| 359 | A | P | Flatness of Optical Flats in diameter of 10 mm – 50 mm | מישוריות של משטחים אופטיים בעלי קוטר 10 – 50 mm | Above 0.05 μm | 0.1 μm FED-GG-0-635 JIS B 7430 JIS B 7431 | Optical flat/parallel מערכת כיוול מקבילונים ועדשה מישורית The uncertainty quoted is for the departure from flatness of parallelism, i.e. the distance separating the two parallel planes, which just enclose by |
| 360 | A | P | Parallelism of Optical Parallels in diameter of 10 mm – 50 mm | מקבילות של משטחים אופטיים בעלי קוטר 10 – 50 mm | Above 0.01 μm | 0.1 μm WI-C009 | The uncertainty quoted is for the departure from flatness of parallelism, i.e. the distance separating the two parallel planes, which just enclose by |

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|--|------------|------|--|--|---|--|---|
| Calibration – Mechanical Quantities - Form, Angle | | | | | | כיוול – גדלים מכניים - צורה, זווית | |
| 361 | A | P;T | Flatness of Granites or Cast iron surfaces in Grade 00 מישוריות של לוחות משטח גרניט וברזל יציקה ברמה 00 | Above 0.1 μm | [1.5+0.8* length] μm | DIN 876 P1,2 ISO 8152 P1,2 GGG-P-463-C | עד 0.09 m ² נבדק באמצעות גשש אורך. מעל 0.09 m ² נבדק במערכת פלסים אלקטרוניים. The uncertainty quoted is for the departure from flatness, straightness, parallelism, or squareness i.e. the distance separating the two parallel planes which, just enclose the surface under consideration (Length in m) |
| 362 | A | P | Straightness, flatness and parallelism of Granite, Cast iron and Steel straightedges in Grade 00 ישרות, מישוריות, מקבילות של סרגל ישרות מתכת או גרניט ברמה 00 | Above 1 μm | 4.3 μm | DIN 874 P.1 | גששי אורך |
| 363 | A | P | Straightness Knife edge, straight edge סרגל שערה | Up to 500 mm] | 1.5 μm | DIN 874 P.2 | מקור אור מונוכרומטי, גששי אורך |
| 364 | A | P | Flatness, Parallels מקבילים | Up to 50*100*400] | 2 μm | DIN 6346 DIN 7151 DIN 7168 | גששי אורך |
| 365 | A | P | Parallelism, Parallels מקבילים | Up to 50*100*400] | 2 μm | DIN 6346 DIN 7151 DIN 7168 | גששי אורך |
| 366 | A | P | Perpendicularity, ניצבות, | Up to 300 mm] | 3.0 μm | DIN-875 | גששי אורך |

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

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|--|------------|------|--|--|---|---|--|
| Calibration – Mechanical Quantities - Form, Angle | | | | | | כיוול – גדלים מכניים - צורה, זווית | |
| 383 | A | P | Universal Box Angles | אביזר דפינה אוניברסאלי (100 mm to 300 mm) | 5 μm | DIN 876 | |
| 384 | A | P | | (300 mm to 600 mm) | 8 μm | | |
| 385 | A | P | Squareness Right angle and box angle plate | ברך, קוביה Up to 600 mm] | [3 + 1 per 100 mm] μm | WI-C050 | מד ניצבות |
| 386 | A | P | Parallelism Right angle and box angle plate | ברך, קוביה Up to 600 mm] | [1 + (1 per 100 mm)] μm | WI-C050 | מד ניצבות |
| 387 | A | P | Perpendicularity Square master | מד ניצבות 600 mm | 2.1 μm | נתוני יצרן WI-C018 | השוואה למדיד אב לניצבות |
| 388 | A | P | Perpendicularity Vee blocks | פריזמות Up to 150 mm] | 2.1 μm | BS 3731 JIS B 7540 | Grade 00 גששי אורך גלייים |
| 389 | A | P | Flatness, Vee blocks | פריזמות Up to 150 mm] | 2.1 μm | BS 3731 JIS B 7540 | Grade 00 גששי אורך גלייים |
| 390 | A | P | Parallelism Vee blocks | פריזמות Up to 150 mm] | 2.1 μm | BS 3731 JIS B 7540 | Grade 00 גששי אורך גלייים |
| 391 | A | P | Angle Sines bars and tables | זווית סרגלים ושולחנות סינוס Up to 500 mm] | 2 " | BS 3064 GGG-B 121b DIN 2273 | Angle is estimated by measuring distance מקבילונים בלוק זוויתי |
| 392 | A | P | Angle Level | פלס ± 5 ° | 0.5 " | DIN 887 BS 958 | 1 μ/m sensitivity מייצר זווית קטנות |
| 393 | A | P | Angle Clinometer | קלינומטר Up to 90 °] | 10 " | DIN 887 BS 958 | מייצר זווית קטנות |

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

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|--|------------|------|---|--|--|---|------------------------------------|
| Calibration – Mechanical Quantities - Form, Angle | | | | | | כיוול – גדלים מכניים - צורה, זווית | |
| 394 | A | P | Angle Bevel protractor | מד זווית מתכוונן up to 360 °) | 3 ´ | BS 1685 | בלוק זוויתי גששי אורך מד ניצבות |
| 395 | A | P;T | Rotational Speed Mechanical tachometer | מהירות סיבוב (סל"ד) מד סל"ד מכני | [1 to 5000] RPM Whichever is greater | Manufacturer instructions WI-C069 | Counter מונה |
| 396 | A | P;T | Rotational Speed Optical tachometer | מהירות סיבוב (סל"ד) מד סל"ד אופטי | [1 to 2500] RPM Whichever is greater | | Function generator מחולל אותות |
| 397 | A | P;T | Rotational Speed Optical tachometer | מהירות סיבוב (סל"ד) מד סל"ד אופטי | [2500 to 99999] RPM | | Function generator מחולל אותות |

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות. התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח.

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|--|------------|------|-----------------------------------|--|---|------------------------|--|
| Calibration – Mechanical Quantities - Hardness Meters | | | | | כיוול – גדלים מכניים - מדי קושיות | | |
| 398 | A | P;T | Rockwell hardness testing machine | HRA [20 to 95] | 0.45 HRA | ASTM E18 ISO 6508-2 | Indirect verification השוואה לחומר יחוס סטנדרטי |
| 399 | A | P;T | | HRBW [10 to 100] | 0.7 HRBW | | |
| 400 | A | P;T | | HRC [10 to 70] | 0.45 HRC | | |
| 401 | A | P;T | | HREW [70 to 100] | 0.9 HREW | | |
| 402 | A | P;T | | HR15N [70 to 94] | 0.5 HR15N | | |
| 403 | A | P;T | | HR30N [42 to 86] | 0.5 HR30N | | |
| 404 | A | P;T | | HR45N [20 to 77] | 0.5 HR45N | | |
| 405 | A | P;T | | HR15TW [67 to 93] | 0.7 HR15TW | | |
| 406 | A | P;T | | HR30TW [29 to 82] | 0.7 HR30TW | | |
| 407 | A | P;T | | HR45TW [10 to 72] | 1.1 HR45TW | | |
| 408 | A | P;T | Brinell hardness testing machine | HBW 2.5 / 187.5 | 2% HBW | ASTM E10 | Indirect verification השוואה לחומר יחוס סטנדרטי |
| 409 | A | P;T | Vickers hardness testing machine | (0.1 to 0.5) HV | 1.5% HV | ASTM E384 | Indirect verification השוואה לחומר יחוס סטנדרטי |
| 410 | A | P;T | | (1 to 100) HV | 1.2% HV | ISO 6507-2 | |

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות. התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח.

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|--|------------|------|--|--|---|--|--|
| Calibration – Mechanical Quantities - Hardness Meters | | | | | | כיוול – גדלים מכניים - מדי קושיות | |
| | | | Shore hardness testing equipment (durometer) | מכשירים למדידת קשיות בשיטת שור Type A Instruments | | ASTM D2240 ISO 21509 ISO 18898 | Direct verification כיוול כח קפיץ ביחידות Shore Durocalibrator |
| 411 | A | P | SHORE A | שור A [0 to 100] Shore | 0.4 SHORE A | | |
| 412 | A | P | Indenter extension | אורך החודרן [0.1 to 2.54] mm | 0.010 mm | | בדיקת פרמטרים של החודרן |
| 413 | A | P | Indenter diameter | קוטר חוד החודרן [0.76 to 0.82] mm | 0.008 mm | | Profile projector Microscope |
| 414 | A | P | Indenter angle | זווית החודרן [34.75° to 35.25°] | 0.05° | | |
| 415 | A | P | Intender diameter | קוטר החודרן [1.1 to 1.4] mm | 0.03 mm | | Indenters with parameters out of the nominal range may be calibrated at stated uncertainties as well |
| 416 | A | P | Presser foot hole diameter | קוטר קדח הבסיס [2.5 to 3.5] mm | 0.03 mm | | |
| 417 | A | P | Presser foot diameter | קוטר בסיס לחיצה [10 to 50] mm | 0.05 mm | | |
| | | | | Type D Instruments | | | |
| 418 | A | P | SHORE D | שור D [10 to 100] Shore | 0.4 SHORE D | | |
| 419 | A | P | Indenter extension | אורך החודרן [0.1 to 2.54] mm | 0.010 mm | | |
| 420 | A | P | Indenter radius | רדיוס חוד החודרן [0.088 to 0.112] mm | 0.008 mm | | |
| 421 | A | P | Indenter angle | זווית החודרן [29° to 31°] | 0.05° | | |
| 422 | A | P | Intender diameter | קוטר החודרן [1.1 to 1.4] mm | 0.03 mm | | |
| 423 | A | P | Presser foot hole diameter | קוטר קדח הבסיס [2.5 to 3.5] mm | 0.03 mm | | |
| 424 | A | P | Presser foot diameter | קוטר בסיס לחיצה [10 to 50] mm | 0.05 mm | | |

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks | |
|---|------------|------|--|--|---|-----------------------------------|---|---------|
| Calibration – Mechanical Quantities - Length | | | | | | כיול – גדלים מכניים - אורך | | |
| 425 | A | P | Gauge Blocks Comparator | מערכת כיול מקבילונים | Up to 100 mm | 0.05 μm | Euramet cg-2 Gauge blocks | |
| 426 | A | P | Length, Gauge Blocks (by Comparison) | אורך, מקבילונים | Class (see note) | | קומפרטור מקבילונים Class C uncertainties apply to the measurement of length of steel gauges by comparison with grade K standards of length of a similar material. Class C uncertainties apply to new grade 0, 1 and 2 gauges to the aforementioned standard and represent the best capability for all grades of used gauges to the aforementioned standard. Class D Class D uncertainties represent the best capability for the measurement of length of tungsten carbide and ceramic gauges by comparison with grade K standards of length of a dissimilar material | |
| 427 | A | P | | | Up to 10 mm} | 0.08 μm | | 0.10 μm |
| 428 | A | P | | | (10 mm to 25 mm] | 0.10 μm | | 0.13 μm |
| 429 | A | P | | | Sizes: 30, 40, 50 | 0.12 μm | | 0.17 μm |
| 430 | A | P | | | Sizes : 60, 70, 75 | 0.15 μm | | 0.21 μm |
| 431 | A | P | | | Sizes : 80, 90, 100 | 0.18 μm | | 0.25 μm |
| 432 | A | P | | | Up to 0.4 in} | 3 μin | | 4 μin |
| 433 | A | P | | | (0.4 to 1 in] | 4 μin | | 5 μin |
| 434 | A | P | | | 2 in | 5 μin | | 7 μin |
| 435 | A | P | | | 3 in | 6 μin | | 8 μin |
| 436 | A | P | 4 in | 7 μin | 10 μin | | | |
| 437 | A | P | Length Gauge Block accessories | אורך, אביזרים מקבילונים | 160 mm | 2 μm | DIN 861 P-2 מכונת מדידה SIP / TRIMOS 305M | |
| 438 | A | P | Length, Length Bars | אורך, מוטות אורך מדיד | Up to 775 mm] | [0.1 + 2×length] μm | BS 5317 ISO 3650 DIN 861 Length bar Length in m | |

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Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks | |
|---|------------|------|--|--|--|--|---|--------|
| Calibration – Mechanical Quantities - Length | | | | | | | כיוול – גדלים מכניים - אורך | |
| 439 | A | P | Length, Length Gauges | אורך, מדיו אורך | Up to 1000 mm] | [0.1 + 2.5×length] μm ISO 3650 DIN 861 ASME B89.1.13 | Length bar Length in m | |
| 440 | A | P | Length, Step Gauge | אורך, מקבילונים מדורגים | Up to 600 mm] | [0.1 + 2.5×length in m] μm נתוני יצרן WI-C019 | Length bar Length in m | |
| 441 | A | P | Length Measuring Machine | מכונת מדידת אורך | Up to 500 mm | [0.1 + 2.5×length] μm Manufacturer Instructions WI-C002 WI-C076 | Length bar Length in m | |
| 442 | A | P | Length, Plain Plug Gauges | אורך, מדיו תקע חלק | [1 to 25.4] mm | 1 μm DIN 7162 DIN 7163 DIN 7164 H28/SEC.6 DIN 2269 | מכונת מדידה SIP / TRIMOS 305M מיקרומטר שולחני | |
| 443 | A | P | | | (25 mm to 100) mm | | | 1.5 μm |
| 444 | A | P | Diameter Plain Rings | טבעות חלקות | [2 mm to 100 mm] | 0.4 μm DIN 2250 | מכונת מדידה SIP / TRIMOS 305M by comparison to gauge block in clamp calibration by comparison to standard plain ring provides lower uncertainties | |
| 445 | A | P | | | (100 mm to 150 mm) | | | 1.5 μm |
| 446 | A | P | | | (150 mm to 205 mm) | | | 2 μm |
| 447 | A | P | Diameter Thread Measuring Cylinders | תיילים לבדיקת מדיד הברגה | [0.1 mm to 6 mm] | 0.7 μm H28/SEC.22A | מכונת מדידה SIP / TRIMOS 305M | |

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

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|---|------------|------|---|---|--|--|--|
| Calibration – Mechanical Quantities - Length | | | | | | כיוול – גדלים מכניים - אורך | |
| 448 | A | P | Pitch Diameter Screw Plug Gauges (parallel) including check and setting Plug | מדיד הברגה זכר – מקביל Plug Diameter [1 mm to 100 mm] | 3 μm | F-STD-H-28 ISO 228/1-2 ISO 1502 | כיוול זווית השן מדיד הברגה זכר קוני – ראה בטכנולוגיה כיוול – גדלים מכניים – צורה, זווית |
| 449 | A | P | | (100 mm to 305 mm) | 5 μm | ISO 2903/4 ISO 7/1,2,9 | |
| 450 | A | P | Pitch Screw Plug Gauges (parallel) including check and setting Plug | פסיעת התבריג מדיד הברגה זכר מקביל Plug Diameter [1 mm to 305 mm] | 1.5 μm | BS 919/1,2,3 BS 849 BS 3409/1,2 BS 4377/2 BS 21 DIN 103/9 | |
| 451 | A | P | Pitch Diameter Screw Plug Gauges (taper) | מדיד הברגה זכר - קוני Plug Diameter [1 mm to 100 mm] | 3 μm | DIN 405 DIN 2999/4 | כיוול זווית השן מדיד הברגה זכר קוני – ראה בטכנולוגיה כיוול – גדלים מכניים – צורה, זווית |
| 452 | A | P | | (100 mm to 305 mm) | 5 μm | B.N.A.e | |
| 453 | A | P | Pitch Screw Plug Gauges (taper) | פסיעת התבריג מדיד הברגה זכר קוני Plug Diameter [1 mm to 305 mm] | 1.5 μm | HELI-COIL WI-C020 WI-C023 WI-C024 | |
| 454 | A | P | Pitch Diameter Thread rings (parallel) | טבעות הברגה – מקבילה Ring diameter [1.2 mm to 3 mm] | Not relevant | F-STD-H 28 ISO 228/1-2 | Go no go test by means of check plug |
| 455 | A | P | | (3 mm to 100 mm) | 4 μm | ISO 1502 | מכונת מדידה |

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks | |
|---|------------|------|---|--|---|--|--|----------------------------|
| Calibration – Mechanical Quantities - Length | | | | | | כיוול – גדלים מכניים - אורך | | |
| 456 | A | P | | (100 mm to 305 mm] | 5 μm | ISO 2903/2904 BS 919/1,23 BS 84 DIN 103/9 DIN 405 DIN 2999/2 B.N.A.e | SIP / TRIMOS 305M | |
| 457 | A | P | Micrometer External | מיקרומטר חיצוני | Up to 2000 mm] | Heads 2.0 μm Setting and extension rods: [1 + 5×length in m] μm | ISO 3611 DIN 863 ASME B89.1.13 JIS B 7502 | מקבילונים מוטות אורך |
| 458 | A | T | | Up to 600 mm] | Heads 3.0 μm Setting and extension rods: [1 + 5×length in m] μm | | | |
| 459 | A | P | Micrometer Internal | מיקרומטר פנים | Up to 300 mm] extension rod to 1000 mm] | Heads 2.0 μm Setting and extension rods [1 + 5×length in m] μm | DIN 863 ASME B89.1.13 | טבעות חלקות מכונת מדידה |
| 460 | A | P;T | Micrometer Depth | מיקרומטר עומק | Up to 250 mm] | Heads 2.0 μm Setting and extension rods [1 + 5×length in m] μm | DIN 863 ASME B89.1.13 | מקבילונים |
| 461 | A | P | Micrometers (indicating digital and electronic) | מיקרומטר (כולל דיגיטלי) | Up to 2000 mm] | [1 + 5×length in m] μm Minimum 1.5 μm | ISO 3611 DIN 863 ASME B89.1.13 JIS B 7502 | מקבילונים מוטות אורך |
| 462 | A | T | | Up to 600 mm] | [1 + 5×length in m] μm Minimum 3.0 μm | | | |
| 463 | A | P | Three point Internal and bore micrometer | מיקרומטר פנים תלת נקודתי | [2 mm to 50 mm] | 2 μm | DIN 863 | טבעות חלקות |
| 464 | A | P | | (50 mm to 150 mm] | 5 μm | Manufacturer Instructions WI-C012 | | |

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|---|------------|------|--|--|---|--|---|---------------------------------------|
| Calibration – Mechanical Quantities - Length | | | | | | כיוול – גדלים מכניים - אורך | | |
| 465 | A | P | Micrometer head | ראש מיקרומטר | Up to 50 mm] | 2 μm | Manufacturer;s instructions WI-C006 | |
| 466 | A | P | Height setting micrometer | מד גובה מיקרומטרי | Up to 300 mm] | Heads 1.0 μm between any two points. Stepped column 2.5 μm Overall performance 3.0 μm | ISO 7863 | מקבילונים, מוטות אורך |
| 467 | A | P | Riser Block | בסיס הגבהה למד גובה | Up to 150 mm] | 2.5 μm | WI-C005 | |
| 468 | A | P | | מיקרומטרי | (150 to 300 mm] | 5 μm | | |
| 469 | A | P;T | Vernier Caliper, depth Gauges | זחון ורנייר | Up to 2000 mm] | Overall performance [10 + 30× length in m] μm | DIN EN ISO 13385-1 DIN EN ISO 13385-2 DIN 862 -1988 | מקבילונים, מוטות אורך, בודק זחונים |
| 470 | A | P;T | Caliper (digital and electronic) | זחון אלקטרוני ודיגיטלי | Up to 2000 mm] | Overall performance [10 + 30× length in m] μm | DIN EN ISO 13385-1 DIN EN ISO 13385-2 DIN 862 -1988 | מקבילונים, מוטות אורך, בודק זחונים |
| 471 | A | P | Micrometer Heads Dial testers | מערכת כיוול חוגנים | Up to 25 mm | 0.2 μm | WI-C028 | Gauge blocks |
| 472 | A | P;T | Height Gauge Electronic microprocessor Controlled height Gauge | מד גובה | Up to 1000 mm] | [1 + 5× length in m] μm | BS 1643 JIS B 7517 | |
| 473 | A | P;T | Dial Indicator | חוגן | Up to 3 mm] | 0.3 μm | DIN 878 | בודק חוגנים מכונת מדידה |
| 474 | A | P;T | Length gauge | גשש אורך | [3-60] mm | 1 μm | DIN 879 JIS B 7509 | |

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח

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Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|---|------------|------|---|--|---|---|---|
| Calibration – Mechanical Quantities - Length | | | | | | כיול – גדלים מכניים - אורך | |
| 475 | A | P;T | | [60-100] mm | 1.5 μm | ANSI B89.1.10M NF E 11-056 ISO 13102 | |
| 476 | A | P;T | Lever type dial indicator Lever type gauge | Up to 3 mm] | 0.3 μm | BS 2795 PT.1 DIN 2270 MIL-I-18422D JIS B 7533 ISO 13102 | בודק חוגנים |
| 477 | A | P;T | Thickness gauge | Up to 50 mm | 2 μm | Manufacturer Instructions WI-C037 | מקבילוני אורך Gauge blocks |
| 478 | A | P;T | Dial caliper gage (external type) | Up to 150 mm | 10 μm | Manufacturer Instructions WI-C037 | מקבילוני אורך Gauge blocks |
| 479 | A | P;T | Dial caliper gage (internal type) | Up to 125 mm | 10 μm | Manufacturer Instructions WI-C035 | מיקרומטר, מקבילוני אורך Micrometer, Gauge blocks |
| 480 | A | P | Feeler Gauge | Up to 1 mm] | 4 μm | DIN 2275 | מיקרומטר |
| 481 | A | P;T | Measuring microscope | Up to 300 mm | [2 + (25/M)] μm | נתוני יצרן WI-C034 | סרגל אופטי M is total magnification |
| 482 | A | P;T | Profile projectors | Up to 300 mm | [2 + (25/M)] μm | נתוני יצרן WI-C034 | סרגל אופטי M is total magnification |
| 483 | A | P | Bore comparators (bore gauge) | [6 mm to 150 mm] | 2 μm | JIS B 7515 MIL-G-26762A MIL-G-26762A | בודק חוגנים טבעות חלקות מיקרומטר |

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The certificate attached is an integral part of the schedule and is numbered identically זהה למספר הנספח חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

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Schedule of Accreditation

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|---|------------|------|--------------------------------|--|---|---|--|
| Calibration – Mechanical Quantities - Length | | | | | כיול – גדלים מכניים - אורך | | |
| 496 | A | P | | 5 mm – 15 mm | 0.020 mm | | |
| 497 | A | P | | 15 mm – 30 mm | 0.050 mm | | |
| 498 | A | P | | Above 30 mm | 0.10 mm | | |
| 499 | A | P:T | Extensometer | מד התארכות [0.01 mm to 50 mm] | 0.004 mm | ASTM E83 ISO 9513 ISO 5893 | Extensometer calibrator |
| 500 | A | P:T | Extensometer (displacement) | מד התארכות [0.01 mm to 1000 mm] | 0.006 mm | Manufacturer Instructions WI-C075 | High precision dial gauge, Length gauge |
| 501 | A | P:T | Length measurements | מדידת אורך Up to 125 mm] | 0.003 mm | Customer requirements WI-C081 | |
| 502 | A | P:T | | (125 mm to 200 mm] | 0.005 mm | | |
| 503 | A | P:T | | (200 mm to 600 mm] | 0.007 mm | | |
| 504 | A | P:T | | (600 mm to 2000 mm] | 0.05 mm | | |

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The certificate attached is an integral part of the schedule and is numbered identically זהו חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

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Schedule of Accreditation

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|---|------------|------|---|--|--|---|--|
| Calibration – Physical Quantities - Optics | | | | | | כיוול – גדלים פיזיקליים - אופטיקה | |
| 505 | A | P,T | Optical emitting devices and Meters מכשיר פולט קרינה אופטית ומד קרינה אופטית | Power הספק 3 n.W to 3 m.w at 270 to 950 nm and 15μW to 150 W at 193 nm to 10600 nm | 3.5% of Reading | In house procedure Based on: IEC 60825 ISO 13694 WI-C203 | |
| 506 | A | P,T | Light emitting devices and Meters מכשיר פולט אור ומד קרינה אופטית | Energy 20μJ to 4 KJ at 193 to 10600 nm | 5% of Reading | In house procedure Based on: IEC 60825 ISO 13694 WI-C203 | |
| 507 | A | P,T | Optical emitting devices and Meters מכשיר פולט קרינה אופטית ומד קרינה אופטית | Frequency & Time תדר וזמן Up to 0.7 MHz Min. Rise/Fall Time 2 nsec | 1 nsec | In house procedure Based on: IEC 60825 ISO 13694 WI-C202 | |
| 508 | A | P,T | Light Meters מד קרינה אופטית | Wavelength 25 nm to 3507 nm | 2x10 ⁻⁴ nm | In house procedure Based on: IEC 60825 ISO 13694 WI-C200 | NIST Atomic Spectra Database |
| 509 | A | P,T | Optical emitting devices and Meters מכשיר פולט קרינה אופטית ומד קרינה אופטית | Wavelength אורך גל 200 nm to 1100 nm | 1 nm | In house procedure Based on: IEC 60825 ISO 13694 WI-C200 | |
| 510 | A | P,T | Light emitting devices and Meters מכשיר פולט אור ומד אור | Light אור 0 to 2.0E+5 lux | 0.5 res or 5.0 % Whichever is greater | In house procedure The CIE 1924 photopic V(λ) luminosity function WI-C201 | |
| 511 | A | P,T | Light emitting devices and Meters מכשיר פולט אור ומד אור | Visible light 6.85*10 ⁻³ cd/m ² to 3120 cd/m ² | 5% of Reading | | Calibration can be given in other units as required. |

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|--|------------|------|---|---|---|---|---|
| Calibration – Physical Quantities - Force, Torque | | | | | | כיוול – גדלים פיזיקליים - כח, מומנט | |
| 512 | A | P,T | Force calibration in tension, force measurement machine | כיוול כח במתיחה, מכונות למדידת כח [0.1 kN to 100 kN] | 1.5 N/kN of verification force | ISO 7500-1 ASTM E4 Manufacturer instructions WI-C056 | מתמר כח Force load cell Calibration can be given in other units as required. 1 N/kN = 0.1% |
| 513 | A | T | Force calibration in tension, material testing machine | כיוול כח במתיחה, מכונות למדידת כח [0.1 kN to 500 kN] | 2.0 N/kN of verification force | | |
| 514 | A | P;T | Force calibration in compression, material testing machine | כיוול כח בלחיצה, מכונות למדידת כח [0.1 kN to 1 MN] | 2.0 N/kN of verification force | | כולל כיוול מכונות בדיקה לפי דרישות תקן ישראלי 26 חלק 4.1 |
| 515 | A | P;T | Force calibration in compression, material testing machine | כיוול כח בלחיצה, מכונות למדידת כח (1 MN to 2.3 MN) | 2.4 N/kN of verification force | | |
| 516 | A | P;T | Force calibration in tension and compression, push pull force measurement machine | כיוול כח בלחיצה ומתיחה מכונות למדידת כוח (0.005 N to 1.2 kN) | 1.0 N/kN of verification force | | משקולות |
| 517 | A | P | Force calibration in tension and compression, Proving devices | כיוול כח בלחיצה ומתיחה [0.005 N to 1.2 kN] | 0.5 N/kN of verification force | ISO 376 Euramet cg-4 | משקולות, מתמר כח |
| 518 | A | P | Proving devices | תאי (טבעות) כוח [1 kN to 20 kN] | 0.7 N/kN of verification force | | |
| 519 | A | P | Force calibration in compression, Proving devices | כיוול כח בלחיצה תאי (טבעות) כוח [20 kN to 1 MN] | 1.0 N/kN of verification force | | |
| 520 | A | P | Proving devices | כיוול כח בלחיצה תאי (טבעות) כוח [1 MN to 2.3 MN] | 2.0 N/kN of verification force | | |
| 521 | A | P | Force calibration in tension, Proving devices | כיוול כח במתיחה תאי (טבעות) כוח [20 kN to 100 kN] | 1.0 N/kN of verification force | | |

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח והוא לנספח זה

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|--|------------|------|--|--|--|--|--|
| Calibration – Physical Quantities - Force, Torque | | | | | | כיוול – גדלים פיזיקליים - כח, מומנט | |
| 522 | A | P | Torque | מומנט [0.01 Nm to 1000 Nm] | 0.5 % OR | ISO 6789 | מתמרי מומנט |
| 523 | A | P | Torque wrenches and drivers | ידית מומנט, מברגת מומנט | | | Calibration can be given in other units as required OR – Of Reading |
| 524 | A | P | Torque | מומנט [0.001 Nm to 0.01 Nm] | 0.25 % OR | BS 7882 | OR – Of Reading |
| 525 | A | P | Mechanical and Electronic torque calibration equipment | מכשירים למדידת מומנט (מכאניים ואלקטרוניים) | [0.01 Nm to 1000 Nm] | Euramet cg-14 Manufacturer's instructions | קורות כיוול ומשקולות |
| 526 | A | T | Torque Mechanical and Electronic torque calibration equipment | מומנט מכשירים למדידת מומנט (מכאניים ואלקטרוניים) | [0.1 Nm to 50 Nm] | WI-C061 | קורות כיוול ומשקולות |
| 527 | A | T | Torque Mechanical and Electronic torque calibration equipment | מומנט מכשירים למדידת מומנט (מכאניים ואלקטרוניים) | (50 Nm to 1000 Nm) | | מתמרי מומנט OR – Of Reading |

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Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks | |
|---|------------|------|--|--|--|--|--|--|
| Calibration – Physical Quantities - Humidity | | | | | | כיוול – גדלים פיזיקליים - לחות | | |
| 528 | A | P | Relative humidity RH meters | לחות יחסית 0 °C to 10 °C (5% rh to 50%] rh | 1.0 % rh | ASTM-E-104-85 NIS 19 OIML R121 Manufacturer instructions WI-C046 | Chilled mirror hygrometer. היגרומטר מד נקודת טל. Humidity and temperature controlled chamber. תא מבוקר לחות וטמפרטורה. | |
| 529 | A | P | RH data loggers RH probes RH transducers | (50% rh 80%] rh | 1.4 % rh | | | |
| 530 | A | P | לחות יחסית | לחות יחסית 10 °C to 45 °C (5% rh to 50%] rh | 0.8 % rh | | | |
| 531 | A | P | מדי לחות | (50% rh 80%] rh | 1.1 % rh | | | |
| 532 | A | P | רגשי לחות | (80% rh 95%] rh | 1.3 % rh | | | |
| 533 | A | P | מתמרי לחות | לחות יחסית 45 °C to 60 °C (5% rh to 50%] rh | 0.8 % rh | | | |
| 534 | A | P | אוגרי נתונים | (50% rh to 80%] rh | 1.0 % rh | | | |
| 535 | A | T | Relative humidity RH probes | לחות יחסית 0 °C to 10 °C [5% rh to 80%] rh | 2.0 % rh | | | Humidity sensors, Humidity and temperature controlled Calibrator |
| 536 | A | T | RH chambers RH meters | לחות יחסית 10 °C to 45 °C [5% rh to 95%] rh | 2.0 % rh | | | |
| 537 | | | לחות יחסית | לחות יחסית 45 °C to 60 °C | | | | |
| 538 | A | T | רגשי לחות תאי לחות מדי לחות | [5% rh to 80%] rh | 2.0 % rh | | | |
| | | | Relative humidity | לחות יחסית 23°C ± 2 °C | | | | |

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|---|------------|------|--|--|---|---------------------|--|
| Calibration – Physical Quantities - Humidity | | | | | כיוול – גדלים פיזיקליים - לחות | | |
| 539 | A | P;T | RH probes | 11.3% rh | 0.5% rh | | Salt solutions in ampoules as humidity standards. |
| 540 | A | P;T | לחות יחסית | 35% rh | 0.7% rh | | |
| 541 | A | P;T | רגשי לחות | 50% rh | 1.1% rh | | |
| 542 | A | P;T | | 75% rh | 1.5% rh | | |
| 543 | A | P;T | | 80% rh | 1.5% rh | | |
| 544 | A | P;T | | 95% rh | 1.6% rh | | |
| 545 | A | P;T | Dew point | נקודת טל [- 40 °C to - 30] °C | 0.35 °C | | Chilled mirror hygrometer היגרומטר מד נקודת טל. |
| 546 | A | P;T | RH meters | [- 30 °C to + 50] °C | 0.2 °C | | |
| 547 | A | P;T | RH transducers לחות יחסית מדי לחות מתמרי לחות | (50 °C to 60] °C | 0.25 °C | | |

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks | |
|---|------------|------|-----------------------------|--|---|---------------------|-------------------------|---|
| Calibration – Physical Quantities - Mass | | | | | כיוול – גדלים פיזיקליים – מסה | | | |
| | A | P | Mass | מסה | 20000 g | 40 mg | OIML R 111-1 | מאזני השוואה |
| | A | P | Weights | משקולות | 10000 g | 5.1 mg | OIML R 52 ASTM-E-617 | Calibration can be given in other units as required. |
| | A | P | | | 5000 g | 2.9 mg | | Intermediate value can be calibrated with an uncertainty interpolated from the next higher and lower values in the table. |
| | A | P | | | 2000 g | 0.63 mg | | |
| | A | P | | | 1000 g | 0.50 mg | | |
| | A | P | | | 500 g | 0.35 mg | | |
| | A | P | | | 200 g | 0.080 mg | | |
| | A | P | | | 100 g | 0.049 mg | | |
| | A | P | | | 50 g | 0.030 mg | | |
| | A | P | | | 20 g | 0.021 mg | | |
| | A | P | | | 10 g | 0.020 mg | | |
| | A | P | | | 5 g | 0.0081 mg | | |
| | A | P | | | 2 g | 0.0063 mg | | |
| | A | P | | | 1 g | 0.0054 mg | | |
| | A | P | | | 0.5 g | 0.0044 mg | | |
| | A | P | | | 0.2 g | 0.0035 mg | | |
| | A | P | | | 0.1 g | 0.0029 mg | | |

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|---|------------|------|-----------------------------|--|--|---------------------|--------------|
| Calibration – Physical Quantities - Mass | | | | | כיוול – גדלים פיזיקליים - מסה | | |
| 5 | A | P | | 0.05 g | 0.0026 mg | | |
| 5 | A | P | | 0.02 g | 0.0025 mg | | |
| 5 | A | P | | 0.01 g | 0.0020 mg | | |
| 5 | A | P | | 0.005 g | 0.0020 mg | | |
| 5 | A | P | | 0.002 g | 0.0020 mg | | |
| 5 | A | P | | 0.001 g | 0.0020 mg | | |
| 5 | A | P | | [0.5 g to 200 g] | 0.1 mg | | מאזני השוואה |
| 5 | A | P | | (200 g to 1 kg] | 0.5 mg | | |
| 5 | A | P | | (1 kg to 5 kg] | 20 mg | | |
| 5 | A | P | | (5 kg to 10 kg] | 30 mg | | |
| 5 | A | P | | (10 kg to 29 kg] | 60 mg | | |
| 5 | A | P;T | מאזניים לא אוטומטיים | (Up to 10 mg] | 2.5 µg | OIML R76 | 1. |

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks | |
|---|------------|------|------------------------------------|--|---|--------------------------------------|---|--------|
| Calibration – Physical Quantities - Mass | | | | | | כיוול – גולים פיזיקליים – מסה | | |
| 5 | A | P;T | Non automatic weighing instruments | כושר הפרדה 0.001 mg או נמוך. | (10 mg to 500 mg] | Manufacturer instructions WI-C044 | Uncertainties depend on the performance of the weighing machine under calibration. 2. Available weights are: OIML Class E2 from 1 mg to 2 kg, OIML Class F1 from 1 mg to 5 kg, OIML Class F2 from 1 mg to 5 kg, OIML Class M1 from 1 mg to 20 kg, OIML Class M2 from 5 kg to 20 kg, test weights 2 × 500 kg. OIML Class E1 weights can be provided on demand. | |
| 5 | A | P;T | Resolution 0.001 mg and less | (500 mg to 2 g] | 5 μg | | | |
| 5 | A | P;T | | (2 g to 5 g] | 7 μg | | | |
| 5 | A | P;T | | (5 g to 20 g] | 10 μg | | | |
| 5 | A | P;T | | (20 g to 50 g] | 25 μg | | | |
| 5 | A | P;T | Non automatic weighing instruments | מאזניים לא אוטומטיים | (Up to 5 g] | | | 15 μg |
| 5 | A | P;T | Resolution 0.01 mg | כושר הפרדה 0.01 mg | (5 g to 50 g] | | | 40 μg |
| 5 | A | P;T | | (50 g to 250 g] | 80 μg | | | |
| 5 | A | P;T | Non automatic weighing instruments | מאזניים לא אוטומטיים | (Up to 50 g] | | | 0.1 mg |
| 5 | A | P;T | Resolution 0.1 mg | כושר הפרדה 0.1 mg | (50 g to 250 g] | | | 0.2 mg |
| 5 | A | P;T | | (250 g to 520 g] | 0.4 mg | | | |
| 5 | A | P;T | Non automatic weighing instruments | מאזניים לא אוטומטיים | (Up to 620 g] | 2 mg | | |
| 5 | A | P;T | Resolution 0.001 g | כושר הפרדה 0.001 g | (620 g – 2 kg] | 3 mg | | |
| 5 | A | P;T | Non automatic weighing instruments | מאזניים | (Up – 5.1 kg] | 0.01 g | | |
| 5 | A | P;T | Resolution 0.01 g | כושר הפרדה 0.01 g | (5.1 kg – 12.1 kg] | 0.02 g | | |
| 5 | A | P;T | | מאזניים לא אוטומטיים | (0 to 8.1 kg] | 0.1 g | | |

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|---|------------|------|------------------------------------|--|--|--------------------------------------|---------|
| Calibration – Physical Quantities - Mass | | | | | | כיוול – גדלים פיזיקליים - מסה | |
| 5 | A | P;T | Non automatic weighing instruments | כושר הפרדה 0.1 g | (8.1 kg to 32 kg) | 0.2 g | |
| 5 | A | P;T | Resolution 0.1 g | | (32 kg to 64 kg) | 0.4 g | |
| 5 | A | P;T | Non automatic weighing instruments | מאזניים לא אוטומטיים | (Up to 50 kg) | 1 g | |
| 5 | A | P;T | Resolution 0.001 kg | כושר הפרדה 0.001 kg | (50 kg to 150 kg) | 2 g | |
| 5 | A | P;T | Non automatic weighing instruments | מאזניים לא אוטומטיים | (Up to 200 kg) | 10 g | |
| 5 | A | P;T | Resolution 0.01 kg | כושר הפרדה 0.01 kg | (200 kg to 500 kg) | 20 g | |
| 5 | A | P;T | Non automatic weighing instruments | מאזניים לא אוטומטיים | (Up 0 to 1000 kg) | 0.1 kg | |
| 6 | A | P;T | Resolution 0.1 kg | כושר הפרדה 0.1 kg | (1000 kg to 2000 kg) | 0.2 kg | |
| 6 | A | P;T | Non automatic weighing instruments | מאזניים לא אוטומטיים | (Up to 10000 kg) | 0.5 kg | |
| | | | כושר הפרדה 0.5 kg | | | | |

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The certificate attached is an integral part of the schedule and is numbered identically להסמכת מעבדות זהה למספר הנספח

Schedule of Accreditation

| <i>Item</i> | <i>Scope Type</i> | <i>Site</i> | <i>Measurand Instrument, Gauge</i> | <i>Range</i> [Including margins] (Does not include margins) | <i>CMC Expressed as an Expanded Uncertainty (95%)</i> | <i>Reference Documents</i> | <i>Remarks</i> |
|---|-------------------|-------------|---|--|---|----------------------------|---|
| Calibration – Physical Quantities - Pressure | | | | | כיוול - גדלים פיזיקליים – לחץ | | |
| 602 | A | P;T | Pneumatic pressure, Gauge. Pressure indicating instruments and gauges Differential pressure | לחץ פניאומאטי, יחסי מדידי לחץ פניאומאטיים לחץ הפרשי | [-1.25 kPa to 1.25 kPa] | 0.7 Pa/kPa OR + 0.05 Pa | OIML-R 101 Euramet cg 17 Manufacturer instructions WI-C047 Druck 610LP 1 Pa/kPa = 0.1% |
| 603 | A | P | Pneumatic pressure Absolute. Pressure indicating instruments and gauges | לחץ פניאומאטי, אבסולוטי מדידי לחץ פניאומאטיים | [1.6 kPa to 7 MPa] | 0.10 Pa/kPa OR + 1 Pa | Budenberg 580H Ruska 2465-754 |
| 604 | A | P | Pneumatic pressure, Gauge. Pressure indicating instruments and gauges | לחץ פניאומאטי, יחסי מדידי לחץ פניאומאטיים | [1.6 kPa to 7 MPa] | 0.10 Pa/kPa OR + 0.35 Pa | Ruska 2465-754 |
| 605 | A | P | Pneumatic pressure, Dead weight tester. Effective area of pneumatic dead weight tester piston | לחץ פניאומאטי כיוול שטח אפקטיבי של בוכנת מאזני לחץ פניאומאטיים | [1.6 kPa to 7 MPa] | 0.10 Pa/kPa OR + 0.35 Pa | Euramet cg 3 Manufacturer instructions WI-C068 Ruska 2465-754 Dead weight tester to be supplied with its mass set Calibration by means of cross float method |
| 606 | A | P | Hydraulic pressure, (gauge) Pressure indicating instruments and gauges | לחץ הידראולי מדידי לחץ | [0.6 MPa to 121 MPa] | 0.20 Pa/kPa | OIML-R 101 Euramet cg 17 Manufacturer instructions WI-C068 DH-Budenberg 580HX |

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|---|------------|------|--|---|---|---|---|
| Calibration – Physical Quantities - Pressure | | | | | | כיוול - גדלים פיזיקליים – לחץ | |
| 607 | A | P | Hydraulic pressure, Dead weight tester. Effective area of hydraulic dead weight tester piston | לחץ הידראולי כיוול שטח אפקטיבי של בוכנת מאזני לחץ הידראוליים | [0.6 MPa to 121 MPa] | 0.20 Pa/kPa Euramet cg 3 Manufacturer instructions WI-C068 | DH-Budenberg 580HX Dead weight tester to be supplied with its mass set Calibration by means of cross float method |
| 608 | A | T | Pneumatic pressure Absolute Pressure indicating instruments and gauges | לחץ פניאומאטי, אבסולוטי מדידי לחץ פניאומאטיים | [1.6 kPa to 0.7 MPa] | 1.5 Pa/kPa OIML-R 101 Euramet cg 17 BHS-IP2 ISO 81060-2 Manufacturer instructions WI-C047 | Druck 610 Druck 603 Druck 104 CONTEC MS200 |
| 609 | A | T | Pneumatic pressure Gauge Pressure indicating instruments and gauges | לחץ פניאומאטי, יחסי מדידי לחץ פניאומאטיים | [1.6 kPa to 7 MPa] | 1.0 Pa/kPa | |
| 610 | A | T | Hydraulic pressure (gauge) Pressure indicating instruments and gauges | לחץ הידראולי מדידי לחץ | [0.6 MPa to 70 MPa] | 1.0 Pa/kPa | |

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Type of Scopes: A- Fixed, C- Flexible

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The certificate attached is an integral part of the schedule and is numbered identically זהו חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks | |
|--|------------|------|------------------------------|--|--|---|-----------------------------------|--|
| Calibration – Physical Quantities - Temperature | | | | | | כיוול – גדלים פיזיקליים - טמפרטורה | | |
| 611 | A | P | Liquid in glass thermometers | תרמומטרים נוזל בזכוכית | [- 80 °C to – 30 °C] | 0.15 °C | ISO 1770 | אמבטיות כיוול |
| 612 | A | P | | | (- 30 °C to 0 °C) | 0.1 °C | ISO 1771 | תרמומטר אב PRT |
| 613 | A | P | | | 0 °C | 0.01 °C | ISO 386 | |
| 614 | A | P | | | (0 °C to 250 °C) | 0.08 °C | JIS 7411 | |
| 615 | A | P | | | (250 °C to 550 °C) | 0.5 °C | JIS 7412 | |
| 616 | A | T | | | [-40 °C to 150 °C] | 1.0 °C | JIS 7542 | |
| 617 | A | T | | | 0 °C | 0.05 °C | ASTM E563 | |
| 618 | A | T | | | (150 °C to 250 °C) | 2.0 °C | ASTM E77 | |
| | | | | | | | BS 593 | |
| | | | | | | | BS 1704 | |
| | | | | | | | Manufacturer instructions WI-C065 | |
| 619 | A | P | PRT | גששי טמפרטורה התנגדות | -196 °C | 0.02 °C | ASTM-E-1137 | Liquid nitrogen |
| 620 | A | P | Measurement by comparison | | [- 90 °C to -80 °C) | 0.2 °C | ASTM-E-644 | PRT may calibrated with its indicator. The uncertainty will be dependent on the indicator performance. |
| 621 | A | P | | | [- 80 °C to 250 °C] | 0.02 °C | IEC 751 | |
| 622 | A | P | | | (250 °C to 550 °C) | 0.05 °C | ITS-90 | |
| 623 | A | P | | | (550 °C to 661 °C) | 0.3 °C | Manufacturer instructions | |
| 624 | A | P | | | 0.01 °C | 0.006 °C | WI-C065 | By WTP |
| 625 | A | T | PRT | גששי טמפרטורה התנגדות | -196 °C | 0.1 °C | | Liquid nitrogen |
| 626 | A | T | Measurement by comparison | | [- 90 °C to – 40 °C] | 0.3 °C | | |
| 627 | A | T | | | [- 40 °C to 140 °C] | 0.1 °C | | |

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|--|------------|------|--|--|--|---|---|
| Calibration – Physical Quantities - Temperature | | | | | | כיוול – גדלים פיזיקליים - טמפרטורה | |
| 628 | A | T | | (140 °C to 250 °C) | 0.3 °C | | |
| 629 | A | T | | (250 °C to 650 °C) | 0.5 °C | | |
| 630 | A | P | TC base metal | -196 °C | 0.14 °C | ASTM-E-230 | Liquid nitrogen |
| 631 | A | P | Measurement by comparison צמודים תרמיים מתכות בסיסיות | [- 90 °C to -80 °C) | 0.2 °C | ASTM-E-220 | TC may calibrated with its indicator. The uncertainty will be dependent on the indicator performance. |
| 632 | A | P | | [- 80 °C to 250 °C) | 0.14 °C | ITS-90 | |
| 633 | A | P | | (250 °C to 550 °C) | 0.4 °C | Manufacturer instructions | |
| 634 | A | P | | (550 °C to 1100 °C) | 1 °C | WI-C065 | |
| 635 | A | T | | -196 °C | 0.3 °C | | |
| 636 | A | T | | [- 80 °C to -40 °C) | 0.5 °C | | |
| 637 | A | T | | [- 40 °C to 250 °C) | 0.3 °C | | |
| 638 | A | T | | (250 °C to 550 °C) | 0.5 °C | | |
| 639 | A | T | | (550 °C to 1100 °C) | 1.5 °C | | |
| 640 | A | P | TC noble metal | [- 50 °C to 550 °C) | 0.4 °C | ASTM-E-230 | TC may calibrated with its indicator. The uncertainty will be dependent on the indicator performance. |
| 641 | A | P | Measurement by comparison צמודים תרמיים מתכות אצילות | (550 °C to 1100 °C) | 1 °C | ASTM-E-220 | |
| 642 | A | T | | [- 50 °C to 250 °C) | 0.5 °C | ITS-90 | |
| 643 | A | T | | (250 °C to 550 °C) | 0.7 °C | Manufacturer instructions | |
| 644 | A | T | | (550 °C to 1100 °C) | 1.5 °C | WI-C065 | |
| 645 | A | P;T | | Freezing chambers Including uniformity | [-90 °C to -50 °C) | 1 °C | DKD-R-5-7 Manufacturer instructions WI-C062 |

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|--|------------|------|--|--|--|--|--|
| Calibration – Physical Quantities - Temperature | | | | | | כיול – גדלים פיזיקליים - טמפרטורה | |
| 646 | A | P;T | Freezers, Incubators, Autoclaves Including uniformity | מקפיאים, אינקובטורים אוטוקלבים כולל בדיקת אחידות | [-50 °C to 151 °C] | 0.5 °C DKD-R-5-7 DIN 12880 Manufacturer instructions WI-C062 | TC, PRT, Data logger |
| 647 | A | P;T | Furnaces Including uniformity | תנורים כולל בדיקת אחידות | [50 °C to 300 °C] | 0.7 °C DKD-R-5-7 DIN 12880 Manufacturer instructions WI-C062 | TC, PRT, Data logger |
| 648 | A | P;T | | (300 °C to 550 °C) | 1 °C | | |
| 649 | A | P;T | | (550 °C to 1100 °C) | 2.5 °C | | |
| 650 | A | P;T | Bathes Including uniformity | אמבט כולל בדיקת אחידות | [-196 °C to 251 °C] | 0.03 °C Manufacturer instructions WI-C062 | SPRT, PRT |
| 651 | A | P;T | | (251 °C to 550 °C) | 0.09 °C | | |
| 652 | A | P | Dry block calibrator | תנור בלוק יבש | [-110 °C to 300 °C] | 0.05 °C EURAMET cg-13 Manufacturer instructions WI-C062 | PRT |
| 653 | A | P | | (300 °C to 650 °C) | 0.3 °C | | |
| 654 | A | P;T | Tube furnace Including uniformity | תנור כיול צינורי כולל בדיקת אחידות | [300 °C to 660 °C] | 0.2 °C Manufacturer instructions WI-C062 | |
| 655 | A | P;T | | (660 °C to 1100 °C) | 1.2 °C | | |
| 656 | A | P;T | Temperature indicators, controllers, recorders and simulators for the resistance sensors | מדי, רשמי ומדמי טמפרטורה עבור מדי התנגדות | -200 °C to 800 °C | 0.01 °C EURAMET cg-11 Manufacturer instructions WI-C067 | Calibration by means of electrical calibration, |
| 657 | A | P | Temperature indicators, controllers, recorders and simulators for the base metal thermocouples | מדי, רשמי ומדמי טמפרטורה עבור צמידים תרמיים מתכות בסיסיות | -200 °C to 1380 °C | 0.2 °C EURAMET cg-11 Manufacturer instructions WI-C067 | Calibration by means of electrical calibration, including cold junction compensation |
| 658 | A | T | | -200 °C to 1380 °C | 0.4 °C | | |

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Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|--|------------|------|---|--|---|---|--|
| Calibration – Physical Quantities - Temperature | | | | | | כיוול – גדלים פיזיקליים - טמפרטורה | |
| 659 | A | P | Temperature indicators, controllers, recorders and simulators for the noble metal thermocouples | 0 °C to 500 °C | 0.5 °C | EURAMET cg-11 Manufacturer instructions WI-C067 | Calibration by means of electrical calibration, including cold junction compensation |
| 660 | A | P | | 500 °C to 1800 °C | 0.3 °C | | |
| 661 | A | T | | 0 °C to 500 °C | 0.9 °C | | |
| 662 | A | T | | 500 °C to 1800 °C | 0.6 °C | | |
| 663 | A | P | Temperature, Infrared Thermometers, | [35 °C to 100 °C] | 0.6 °C | ASTM E2847 Manufacturer instructions WI-C080 | IR Calibrator |
| 664 | A | P | | (100 °C to 200 °C] | 1.0 °C | | |
| 665 | A | P | | (200 °C to 350 °C] | 1.7 °C | | |
| 666 | A | P | | (350 °C to 500 °C] | 2.5 °C | | |

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The certificate attached is an integral part of the schedule and is numbered identically. התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח.

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

Schedule of Accreditation

| Item | Scope Type | Site | Measurand Instrument, Gauge | Range [Including margins] (Does not include margins) | CMC Expressed as an Expanded Uncertainty (95%) | Reference Documents | Remarks |
|---|------------|------|---|--|---|---|--|
| Calibration – Small (up to 2L) Volume Volumetric Instruments | | | | | כיוול – כיוול מכשירים וולומטריים – נפחים קטנים עד 2 ליטר | | |
| | | | Liquid volume, Piston-operated volumetric apparatus | נפח נוזלים כיוול מכשירים וולומטריים בהנע בוכנה Nominal value | | ISO 8655- Part 1,2,3,4,5,6 ISO/TR 20461 Manufacturer instructions WI-C074 | מתקן נפח מופעל בוכנה POVA Intermediate volumes may be calibrated with uncertainty as for the higher volume value |
| 667 | A | P | | 1 µl | 0.030 µl | | |
| 668 | A | P | | 2 µl | 0.040 µl | | |
| 669 | A | P | | 5 µl | 0.050 µl | | |
| 670 | A | P | | 10 µl | 0.060 µl | | |
| 671 | A | P | | 20 µl | 0.080 µl | | |
| 672 | A | P | | 50 µl | 0.21 µl | | |
| 673 | A | P | | 100 µl | 0.27 µl | | |
| 674 | A | P | | 200 µl | 0.72 µl | | |
| 675 | A | P | | 500 µl | 1.3 µl | | |
| 676 | A | P | | 1000 µl | 1.8 µl | | |
| 677 | A | P | | 2000 µl | 5.4 µl | | |
| 678 | A | P | | 5000 µl | 9.6 µl | | |
| 679 | A | P | | 10000 µl | 15 µl | | |
| 680 | A | P | | 20000 µl | 20 µl | | |
| 681 | A | P | | 25000 µl | 25 µl | | |
| 682 | A | P | | 50000 µl | 35 µl | | |

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